Notice of References Cited Application/Control No. 10/757,199 Examiner Tai Van Nguyen Applicant(s)/Patent Under Reexamination LONG ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,032,815	07-1991	Kobayashi et al.	336/83
	В	US-5,302,932	04-1994	Person et al.	336/200
	С	US-4,543,553	09-1985	Mandai et al.	336/83
	D	US-3,614,554	10-1971	Shield et al.	257/531
	Е	US-3,731,005	05-1973	Shearman, Paul M.	360/123
	F	US-5,392,019	02-1995	Ohkubo, Akira	336/200
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP- 06-119386	05-1994	Japan	iKuta Takanori	H01F 17/00
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	w					
	x					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.